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L15: Entry 1 of 4

File: USPT

Feb 20, 1996

US-PAT-NO: 5493729

DOCUMENT-IDENTIFIER: US 5493729 A

TITLE: Knowledge data base processing system and expert system

DATE-ISSUED: February 20, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Nigawara; Seiitsu	Hitachi			JP
Namba; Shigeaki	Hitachi			JP
Kohmoto; Hiroshi	Hitachi			JP

US-CL-CURRENT: 706/52; 706/60

Full	Title	Citation	Front	Review	Classification	Date	Reference	References	Abstracts	Claims	KMC	Drawings
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☒ 2. Document ID: US 5005143 A

L15: Entry 2 of 4

File: USPT

Apr 2, 1991

US-PAT-NO: 5005143

DOCUMENT-IDENTIFIER: US 5005143 A

TITLE: Interactive statistical system and method for predicting expert decisions

DATE-ISSUED: April 2, 1991

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Altschuler; Martin D.	Wallingford	PA		
Whittington; Richard	Media	PA		

US-CL-CURRENT: 702/181; 706/46, 706/52, 706/924

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 3. Document ID: DE 4108310 A, JP 3268529 B2, US 5493729 A, DE 4108310 C2

L15: Entry 3 of 4

File: DWPI

Sep 26, 1991

DERWENT-ACC-NO: 1991-289202

DERWENT-WEEK: 200222

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TITLE: Knowledge base processing and expert system - stores indices representing certainty grade of casual relationship between occurrence and others relevant to it

INVENTOR: KOHMOTO, H; NAMBA, S ; NIGAWARA, S

PRIORITY-DATA: 1990JP-0063697 (March 14, 1990)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
DE 4108310 A	September 26, 1991		000	
JP 3268529 B2	March 25, 2002		019	G06F009/44
US 5493729 A	February 20, 1996		023	G06F015/18
DE 4108310 C2	October 22, 1998		000	G06F015/18

INT-CL (IPC): G06F 9/44; G06F 15/18

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 4. Document ID: US 5005143 A

L15: Entry 4 of 4

File: DWPI

Apr 2, 1991

DERWENT-ACC-NO: 1991-117187

DERWENT-WEEK: 199116

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TITLE: Interactive statistical system and predicting expert decisions - repeating random value generation and corresponding responses until sufficient are given to achieve set statistical significance

PRIORITY-DATA: 1989US-0411911 (September 25, 1989), 1987US-0065304 (June 19, 1987)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
US 5005143 A	April 2, 1991		000	

INT-CL (IPC): G06F 9/00; G06F 15/42

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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Terms	Documents
(5,005,143 5,493,729).pn.	4

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<u>L15</u>	(5,005,143 5,493,729).pn.	4	<u>L15</u>
<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>

L1 6,535,865.pn.

2 L1

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☐ 1. Document ID: US 5133046 A

Using default format because multiple data bases are involved.

L16: Entry 1 of 2

File: USPT

Jul 21, 1992

US-PAT-NO: 5133046

DOCUMENT-IDENTIFIER: US 5133046 A

TITLE: Computer-based diagnostic expert system organized according to Bayesian theory

DATE-ISSUED: July 21, 1992

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Kaplan; Stanley	Rancho Palas Verdes			CA

US-CL-CURRENT: 706/52; 706/912, 706/914

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KMC	Draw De
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☐ 2. Document ID: US 5133046 A

L16: Entry 2 of 2

File: DWPI

Jul 21, 1992

DERWENT-ACC-NO: 1992-268277

DERWENT-WEEK: 199232

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TITLE: Computer-based diagnostic expert system organised according to bayesian theory - generates diagnosis in form of probability distributions, responding to evidence in discrete time trajectories and data from knowledge base

INVENTOR: KAPLAN, S

PRIORITY-DATA: 1991US-0637190 (January 3, 1991)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
<u>US 5133046 A</u>	July 21, 1992		022	G06F015/18

INT-CL (IPC): G06F 15/18

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Drawings
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Terms	Documents
5,133,046.pn.	2

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<u>L16</u>	5,133,046.pn.	2	<u>L16</u>
<u>L15</u>	(5,005,143 5,493,729).pn.	4	<u>L15</u>
<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>

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1 Probabilistic relevance relations

Geiger, D.; Heckerman, D.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on , Volume: 28 , I
1 , Jan. 1998

Pages:17 - 25

[\[Abstract\]](#) [\[PDF Full-Text \(560KB\)\]](#) **IEEE JNL**

2 Decision-theoretic case-based reasoning

Breese, J.S.; Heckerman, D.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on , Volume: 26 , I
6 , Nov. 1996

Pages:838 - 842

[\[Abstract\]](#) [\[PDF Full-Text \(552KB\)\]](#) **IEEE JNL**

3 Causal independence for probability assessment and inference using Bayesian networks

Heckerman, D.; Breese, J.S.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on , Volume: 26 , I
6 , Nov. 1996

Pages:826 - 831

[\[Abstract\]](#) [\[PDF Full-Text \(604KB\)\]](#) **IEEE JNL**

4 An approximate nonmyopic computation for value of information

Heckerman, D.; Horvitz, E.; Middleton, B.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume:
15 , Issue: 3 , March 1993

Pages:292 - 298

[\[Abstract\]](#) [\[PDF Full-Text \(604KB\)\]](#) **IEEE JNL**

5 Separating appearance from deformation

Jojic, N.; Simard, P.; Frey, B.J.; Heckerman, D.;

Computer Vision, 2001. ICCV 2001. Proceedings. Eighth IEEE International
Conference on , Volume: 2 , 7-14 July 2001

Pages:288 - 294 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(788KB\)\]](#) **IEEE CNF**

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1 On compatible priors for Bayesian networks

Cowell, R.G.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 18 , Issue: 9 , Sept. 1996

Pages:901 - 911

[\[Abstract\]](#) [\[PDF Full-Text \(916KB\)\]](#) **IEEE JNL**

2 Sequential model criticism in probabilistic expert systems

Cowell, R.G.; Dawid, A.P.; Spiegelhalter, D.J.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 15 , Issue: 3 , March 1993

Pages:209 - 219

[\[Abstract\]](#) [\[PDF Full-Text \(904KB\)\]](#) **IEEE JNL**

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<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
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☐ 1. Document ID: US 5751915 A

Using default format because multiple data bases are involved.

L7: Entry 1 of 9

File: USPT

May 12, 1998

US-PAT-NO: 5751915

DOCUMENT-IDENTIFIER: US 5751915 A

TITLE: Elastic fuzzy logic system

DATE-ISSUED: May 12, 1998

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Werbos; Paul J.	College Park	MD	20740	

US-CL-CURRENT: [706/4](#); [706/2](#), [706/52](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Generate	Attachments	Claims	KMIC	Draw D
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☐ 2. Document ID: US 5604841 A

L7: Entry 2 of 9

File: USPT

Feb 18, 1997

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: [706/11](#); [706/52](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Generate	Attachments	Claims	KMIC	Draw D
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☐ 3. Document ID: US 5537644 A

L7: Entry 3 of 9

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using qualitative physics

DATE-ISSUED: July 16, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		

US-CL-CURRENT: 706/52; 702/33, 702/35

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Draw. De
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☐ 4. Document ID: US 5522014 A

L7: Entry 4 of 9

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

**** See image for Certificate of Correction ****

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

DATE-ISSUED: May 28, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Clark; Robert T.	Enfield	CT		
Hamilton; Thomas P.	South Windsor	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Draw. De
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☐ 5. Document ID: US 5353381 A

L7: Entry 5 of 9

File: USPT

Oct 4, 1994

US-PAT-NO: 5353381
DOCUMENT-IDENTIFIER: US 5353381 A

TITLE: Intelligent test selection for machine failure isolation using qualitative physics

DATE-ISSUED: October 4, 1994

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Perveiler; Kevin J.	Monroe	CT		
Jacobsen; Carol E.	Shelton	CT		

US-CL-CURRENT: 706/52

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 6. Document ID: US 5216749 A

L7: Entry 6 of 9

File: USPT

Jun 1, 1993

US-PAT-NO: 5216749
DOCUMENT-IDENTIFIER: US 5216749 A

TITLE: Core predictions for qualitative physics

DATE-ISSUED: June 1, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 7. Document ID: US 5202955 A

L7: Entry 7 of 9

File: USPT

Apr 13, 1993

US-PAT-NO: 5202955
DOCUMENT-IDENTIFIER: US 5202955 A

TITLE: Dynamic assumption ordering for qualitative physics

DATE-ISSUED: April 13, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
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Hamilton; Thomas P. South Windsor CT
Jacobsen; Carol E. Shelton CT

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw D
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☐ 8. Document ID: US 5187773 A

L7: Entry 8 of 9

File: USPT

Feb 16, 1993

US-PAT-NO: 5187773

DOCUMENT-IDENTIFIER: US 5187773 A

**** See image for Certificate of Correction ****

TITLE: Machine failure isolation using qualitative physics

DATE-ISSUED: February 16, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Jacobsen; Carol E.	Shelton	CT		
Perveiler; Kevin J.	Monroe	CT		

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw D
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☐ 9. Document ID: US 5138694 A

L7: Entry 9 of 9

File: USPT

Aug 11, 1992

US-PAT-NO: 5138694

DOCUMENT-IDENTIFIER: US 5138694 A

TITLE: Parallel processing qualitative reasoning system

DATE-ISSUED: August 11, 1992

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windosr	CT		

US-CL-CURRENT: 706/52; 706/10

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw D
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L4 and probabil\$6 and debug and diagnos\$6	9

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☐ 1. Document ID: US 5604841 A

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L8: Entry 1 of 3

File: USPT

Feb 18, 1997

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/11; 706/52

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 2. Document ID: US 5537644 A

L8: Entry 2 of 3

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using qualitative physics

DATE-ISSUED: July 16, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		

US-CL-CURRENT: 706/52; 702/33, 702/35

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 3. Document ID: US 5522014 A

L8: Entry 3 of 3

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

**** See image for Certificate of Correction ****

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

DATE-ISSUED: May 28, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Clark; Robert T.	Enfield	CT		
Hamilton; Thomas P.	South Windsor	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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Search Results - Record(s) 1 through 2 of 2 returned.

☐ 1. Document ID: US 20020116351 A1

Using default format because multiple data bases are involved.

L9: Entry 1 of 2

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	CO	DK	
Wright, David W.	Fort Collins		US	

US-CL-CURRENT: 706/21

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw De
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☐ 2. Document ID: US 6012152 A

L9: Entry 2 of 2

File: USPT

Jan 4, 2000

US-PAT-NO: 6012152

DOCUMENT-IDENTIFIER: US 6012152 A

**** See image for Certificate of Correction ****

TITLE: Software fault management system

DATE-ISSUED: January 4, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Douik; Samir	Sainte Anne de Bellevue			CA
Boutaba; Raouf	Montreal			CA

US-CL-CURRENT: 714/26

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw D
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Terms	Documents
probabil\$6 and troubleshooters and diagnostics	2

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<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>
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L14: Entry 1 of 16

File: PGPB

Sep 4, 2003

PGPUB-DOCUMENT-NUMBER: 20030167111

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030167111 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 4, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Kipersztok, Oscar	Redmond	WA	US	
Rein-Weston, Karl J.	Seattle	WA	US	
Nelson, Scott L.	Issaquah	WA	US	
Dildy, Glenn A.	Sammamish	WA	US	
Chew, Susan Chan	Issaquah	WA	US	

US-CL-CURRENT: [701/29](#); [702/185](#), [714/25](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw De
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☐ 2. Document ID: US 20020183988 A1

L14: Entry 2 of 16

File: PGPB

Dec 5, 2002

PGPUB-DOCUMENT-NUMBER: 20020183988

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020183988 A1

TITLE: Model selection for decision support systems

PUBLICATION-DATE: December 5, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	CO	DK	
Schreckengast, James	Fort Collins		US	

US-CL-CURRENT: 703/2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMIC	Draw. De
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☐ 3. Document ID: US 20020138184 A1

L14: Entry 3 of 16

File: PGPB

Sep 26, 2002

PGPUB-DOCUMENT-NUMBER: 20020138184

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020138184 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 26, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Kipersztok, Oscar	Redmond	WA	US	
Rein-Weston, Karl J.	Seattle	WA	US	
Walker, Nicholas James	Seattle	WA	US	
Chew, Susan Chan	Issaquah	WA	US	

US-CL-CURRENT: 701/29; 340/945

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMIC	Draw. De
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☐ 4. Document ID: US 20020116351 A1

L14: Entry 4 of 16

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	CO	DK	
Wright, David W.	Fort Collins		US	

US-CL-CURRENT: 706/21

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMIC	Draw. De
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☐ 5. Document ID: US 20020044296 A1

L14: Entry 5 of 16

File: PGPB

Apr 18, 2002

PGPUB-DOCUMENT-NUMBER: 20020044296

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020044296 A1

TITLE: Authoring tool for bayesian network diagnostic systems

PUBLICATION-DATE: April 18, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund		DK	

US-CL-CURRENT: 358/1.14; 358/1.15

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawn De
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☐ 6. Document ID: US 20010011260 A1

L14: Entry 6 of 16

File: PGPB

Aug 2, 2001

PGPUB-DOCUMENT-NUMBER: 20010011260

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20010011260 A1

TITLE: Automated diagnosis of printer systems using bayesian networks

PUBLICATION-DATE: August 2, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	ID	DK	
Jensen, Finn V.	Broenderslev	ID	DK	
Kjaerulff, Uffe	Aalborg		DK	
Pelletier, Paul A.	Boise		US	
Jensen, Lasse Rostrup	Aalborg		DK	
Parker, Marilyn A.	Boise		US	
Bogorad, Janice L.	Allerod		DK	

US-CL-CURRENT: 706/46

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawn De
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☐ 7. Document ID: US 6591257 B1

L14: Entry 7 of 16

File: USPT

Jul 8, 2003

US-PAT-NO: 6591257
DOCUMENT-IDENTIFIER: US 6591257 B1

TITLE: Apparatus and method for a compositional decision support reasoning system

DATE-ISSUED: July 8, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Martinka; Joseph J	Sunnyvale	CA		
Collins; Patricia	Mountain View	CA		
Forman; George H.	Port Orchard	WA		
Kirshenbaum; Evan R.	Mountain View	CA		
Seetharaman; Aparna	Palo Alto	CA		

US-CL-CURRENT: 706/46

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw De
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☐ 8. Document ID: US 6574537 B2

L14: Entry 8 of 16

File: USPT

Jun 3, 2003

US-PAT-NO: 6574537
DOCUMENT-IDENTIFIER: US 6574537 B2

TITLE: Diagnostic system and method

DATE-ISSUED: June 3, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Kipersztok; Oscar	Redmond	WA		
Rein-Weston; Karl J.	Seattle	WA		
Nelson; Scott L.	Issaquah	WA		
Dildy; Glenn A.	Sammamish	WA		
Walker; Nicholas James	Seattle	WA		
Chew; Susan Chan	Issaquah	WA		

US-CL-CURRENT: 701/29; 701/33, 701/34, 702/185, 714/25

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw De
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☐ 9. Document ID: US 6484010 B1

L14: Entry 9 of 16

File: USPT

Nov 19, 2002

US-PAT-NO: 6484010
DOCUMENT-IDENTIFIER: US 6484010 B1

**** See image for Certificate of Correction ****

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 19, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sheehan; Kathleen M.	Skillman	NJ		

US-CL-CURRENT: [434/362](#); [434/118](#), [434/322](#), [434/350](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachment	Claims	KWIC	Draw De
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☐ 10. Document ID: US 6394952 B1

L14: Entry 10 of 16

File: USPT

May 28, 2002

US-PAT-NO: 6394952

DOCUMENT-IDENTIFIER: US 6394952 B1

**** See image for Certificate of Correction ****

TITLE: Point of care diagnostic systems

DATE-ISSUED: May 28, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Anderson; Emory V.	Danville	CA		
Lapointe; Jerome	Oakland	CA		
Martinez; Ricardo	Santa Cruz	CA		
Marzolf; Gail	Cupertino	CA		
Pong; Ronald	San Jose	CA		
Jones; Lynn	Mountainview	CA		
Hussa; Robert O.	Sunnyvale	CA		
Nemec; Edward	Duluth	GA		
Senyei; Andrew E.	La Jolla	CA		
DeSieno; Duane	La Jolla	CA		

US-CL-CURRENT: [600/300](#); [435/4](#), [436/814](#), [600/304](#), [600/310](#), [600/351](#), [600/573](#), [600/584](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachment	Claims	KWIC	Draw De
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☐ 11. Document ID: US 6267722 B1

L14: Entry 11 of 16

File: USPT

Jul 31, 2001

US-PAT-NO: 6267722

DOCUMENT-IDENTIFIER: US 6267722 B1

**** See image for Certificate of Correction ****

TITLE: Point of care diagnostic systems

DATE-ISSUED: July 31, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Anderson; Emory V.	Danville	CA		
Nemec; Edward	Duluth	GA		
Lapointe; Jerome	Oakland	CA		
DeSieno; Duane	La Jolla	CA		
Martinez; Ricardo	Santa Cruz	CA		
Marzolf; Gail	Cupertino	CA		
Pong; Ronald	San Jose	CA		
Jones; Lynn	Mountain View	CA		
Hussa; Robert O.	Sunnyvale	CA		
Senyei; Andrew E.	La Jolla	CA		

US-CL-CURRENT: 600/300; 435/4, 436/811, 436/814, 600/304, 600/310, 600/345,
600/573, 600/584

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw De
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☐ 12. Document ID: US 6219626 B1

L14: Entry 12 of 16

File: USPT

Apr 17, 2001

US-PAT-NO: 6219626

DOCUMENT-IDENTIFIER: US 6219626 B1

**** See image for Certificate of Correction ****

TITLE: Automated diagnostic system

DATE-ISSUED: April 17, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Steinmetz; Michael J.	Kissimmee	FL	34743	
Kirst; Michael E.	Kissimmee	FL	34744	

US-CL-CURRENT: 702/183; 702/182, 702/185, 714/25, 714/46

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw De
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☐ 13. Document ID: US 6144838 A

L14: Entry 13 of 16

File: USPT

Nov 7, 2000

US-PAT-NO: 6144838

DOCUMENT-IDENTIFIER: US 6144838 A

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 7, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sheehan; Kathleen M.	Skillman	NJ		

US-CL-CURRENT: [434/362](#); [434/118](#), [434/322](#), [434/350](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw D
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☒ 14. Document ID: US 6076083 A

L14: Entry 14 of 16

File: USPT

Jun 13, 2000

US-PAT-NO: 6076083

DOCUMENT-IDENTIFIER: US 6076083 A

TITLE: Diagnostic system utilizing a Bayesian network model having link weights updated experimentally

DATE-ISSUED: June 13, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Baker; Michelle	New York	NY	10025	

US-CL-CURRENT: [706/52](#); [706/45](#), [706/46](#), [706/61](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw D
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☐ 15. Document ID: US 5544308 A

L14: Entry 15 of 16

File: USPT

Aug 6, 1996

US-PAT-NO: 5544308

DOCUMENT-IDENTIFIER: US 5544308 A

TITLE: Method for automating the development and execution of diagnostic reasoning software in products and processes

DATE-ISSUED: August 6, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Giordano; Gerard J.	Sparta	NJ		
deMare; Gregory	Sparta	NJ		
Longendorfer; Betsy	Ridgewood	NJ		
Granieri; Michael N.	Springfield	VA		

Giordano; John P.	Sparta	NJ
Nolan; Mary E.	Lafayette	NJ
Levy; Ford	Pleasantville	NY

US-CL-CURRENT: 714/26; 706/45, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Draw De
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☐ 16. Document ID: US 5130936 A

L14: Entry 16 of 16

File: USPT

Jul 14, 1992

US-PAT-NO: 5130936

DOCUMENT-IDENTIFIER: US 5130936 A

TITLE: Method and apparatus for diagnostic testing including a neural network for determining testing sufficiency

DATE-ISSUED: July 14, 1992

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sheppard; John W.	Glen Burnie	MD		
Simpson; William R.	Edgewater	MD		
Graham; Jerry L.	Baldwin	MD		

US-CL-CURRENT: 702/123; 128/925, 324/73.1, 706/10, 706/20, 706/911

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Draw De
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Przytula, K.W.; Thompson, D.;

Aerospace Conference Proceedings, 2000 IEEE , Volume: 5 , 18-25 March 2000
 Pages:193 - 200 vol.5

[\[Abstract\]](#) [\[PDF Full-Text \(688 KB\)\]](#) **IEEE CNF**

2 Constructing Bayesian networks for medical diagnosis from incomplete and partially correct statistics

Nikovski, D.;

Knowledge and Data Engineering, IEEE Transactions on , Volume: 12 , Issue: 4 , July-Aug. 2000
 Pages:509 - 516

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE JNL**

3 A probabilistic approach to residual processing for vehicle fault detection

Schwall, M.L.; Gerdes, J.C.;

American Control Conference, 2002. Proceedings of the 2002 , Volume: 3 , 8-10 May 2002
 Pages:2552 - 2557 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(614 KB\)\]](#) **IEEE CNF**

4 A smart diagnostic system for Doppler ultrasonography

Das, B.; Banerjee, S.;

Bioengineering Conference, 2002. Proceedings of the IEEE 28th Annual Northeast , 20-21 April 2002
 Pages:275 - 276

[\[Abstract\]](#) [\[PDF Full-Text \(333 KB\)\]](#) IEEE CNF

5 Extending the feature dictionary to support sophisticated feature interaction and classification

Samuels, W.B.; Evens, M.; Naeymi-Rad, F.; Rosenthal, R.; Naeymirad, S.; Le Trace, D.; Carmony, L.;

Computer-Based Medical Systems, 1989. Proceedings., Second Annual IEEE Symposium on , 26-27 June 1989

Pages:29 - 35

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6 Summary and applicability of analog fault detection/isolation techniques

Molnar, J.A.;

AUTOTESTCON '97. 1997 IEEE Autotestcon Proceedings , 22-25 Sept. 1997

Pages:383 - 389

[\[Abstract\]](#) [\[PDF Full-Text \(608 KB\)\]](#) IEEE CNF

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